11th IEEE European Test Symposium

Hilton Hotel, Southampton, United Kingdom
May 21-25, 2006
http://www.ieee-ets.org

Student Forum – Call for Submissions

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics, and new trends in the area of electronic-based circuit and system testing. In 2006, ETS will take place in Southampton, the historic port on the south coast of England. ETS'06 is being organized by the University of Southampton and sponsored by the Test Technology Technical Council (TTTC) of the IEEE Computer Society.

The Student Forum is a new initiative at ETS'06, included as part of the symposium program. It allows students to publicly present and discuss their research work. Students attending ETS'06 can benefit from the symposium's technical program and tutorials. Additionally, attending students can build contacts with industry (for application of research results, sponsored projects, internships, and potential future employment) and academia (for further studies and research collaborations).

Students working in the area of electronic test are invited to make submissions describing their research work and highlighting the motivations and the likely innovations of their research. On-going work, especially work which is not sufficiently mature to be published in the formal proceedings and presented in the formal track is invited for submission to the Student Forum. Accepted papers will be presented in the informal track at ETS'06 and will be published in the Informal Digest of Papers.

The areas of interest of ETS'06 include (but are not limited to) the following topics:

- *Analog, Mixed-Signal, RF Test*
- *ATE Hardware and Software*
- *Automatic Test Generation*
- *Board and System Test*
- *Built-In Self Test (BIST)*
- *Current-Based Test*
- *Defect and Fault Tolerance*
- *Delay and Performance Test*
- *Design for Test(ability) (DfT)*
- *Design Verification and Validation*
- *Diagnosis and Debug*
- *(Embedded) System Test*
- *Failure Analysis*
- *Fault Modeling and Simulation*
- *High-Level DfT and TPG*
- *High-Speed IO/Interconnect Test*
- *Memory Test and Repair*
- *MEMS and Nanotechnology Test*
- *Microprocessor Test*
- *Nanometer Technologies Test*
- *On-Line and Off-Line Test*
- *Power Issues in Test*
- *Self-Repair Methodologies*
- *Signal Integrity Test*
- *Standards in Testing*
- *System-in-Package (SiP) Test*
- *System-on-Chip (SoC) Test*
- *Test Data Compression*
- *Test of Reconfigurable Systems*
- *Test Quality and Reliability*
- *Test(ability) Synthesis*
- *Thermal Test*
- *Yield Analysis and Enhancement*

Submissions

Detailed submission instructions, including selection criteria and publication policies, for the various types of contributions are posted on the ETS'06 web page; electronic submission of PDF files via this page is required.

Student Grants

A number of grants are provided by the UK's Engineering and Physical Sciences Research Council (EPSRC), aimed at encouraging student participation. Grants are meant for travel, accommodation, and symposium registration. Preference for student grants is given to students who:

- are the first author of a paper accepted (in any submission category) at ETS,
- will present an accepted paper at ETS, and
- are attending ETS for the first time.

EPSRC
Engineering and Physical Sciences
Research Council

Key Dates for Submissions and Student Grant Applications

- Submission deadline : **December 9, 2005**
- Notification of acceptance : **February 11, 2006**
- Camera-ready manuscript : **March 11, 2006**
- Student Grant application : **December 9, 2005**
- Notification of acceptance : **February 11, 2006**

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For further information, visit the ETS web page at: **http://www.ieee-ets.org**

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